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Details

Product Status	Active
Core Processor	HCS12
Core Size	16-Bit
Speed	25MHz
Connectivity	CANbus, I ² C, SCI, SPI
Peripherals	PWM, WDT
Number of I/O	91
Program Memory Size	128KB (128K x 8)
Program Memory Type	FLASH
EEPROM Size	2K x 8
RAM Size	8K x 8
Voltage - Supply (Vcc/Vdd)	2.35V ~ 5.25V
Data Converters	A/D 16x10b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	112-LQFP
Supplier Device Package	112-LQFP (20x20)
Purchase URL	https://www.e-xfl.com/product-detail/nxp-semiconductors/mc9s12dg128cpve

Version Number	Revision Date	Effective Date	Author	Description of Changes
V02.07	29 Jan 2003	29 Jan 2003		<p>Added 3L40K mask set in section 1.6</p> <p>Corrected register entries in section 1.5.1 "Detailed Memory Map"</p> <p>Updated description for ROMCTL in section 2.3.31</p> <p>Updated section 4.3.3 "Unsecuring the Microcontroller"</p> <p>Corrected and updated device-specific information for OSC (section 8.1) & Byteflight (section 15.1)</p> <p>Updated footnote in Table A-4 "Operating Conditions"</p> <p>Changed reference of VDDM to VDDR in section A.1.8</p> <p>Removed footnote on input leakage current in Table A-6 "5V I/O Characteristics"</p>
V02.08	26 Feb 2003	26 Feb 2003		<p>Added part numbers MC9S12DT128E, MC9S12DG128E, and MC9S12DJ128E in "Preface" and related part number references</p> <p>Removed mask sets 0L40K and 2L40K from Table 1-3</p>
V02.09	15 Oct 2003	15 Oct 2003		<p>Replaced references to HCS12 Core Guide by the individual HCS12 Block guides in Table 0-2, section 1.5.1, and section 6; updated Fig.3-1 "Clock Connections" to show the individual HCS12 blocks</p> <p>Corrected PIM module name and document order number in Table 0-2 "Document References"</p> <p>Corrected ECT pulse accumulators description in section 1.2 "Features"</p> <p>Corrected KWP5 pin name in Fig 2-1 112LQFP pin assignments</p> <p>Corrected pull resistor CTRL/reset states for PE7 and PE4-PE0 in Table 2.1 "Signal Properties"</p> <p>Mentioned "S12LRAE" bootloader in Flash section 17</p> <p>Corrected footnote on clamp of TEST pin under Table A-1 "Absolute Maximum Ratings"</p> <p>Corrected minimum bus frequency to 0.25MHz in Table A-4 "Operating Conditions"</p> <p>Replaced "burst programming" by "row programming" in A.3 "NVM, Flash and EEPROM"</p> <p>Corrected blank check time for EEPROM in Table A-11 "NVM Timing Characteristics"</p> <p>Corrected operating frequency in Table A-18 "SPI Master/Slave Mode Timing Characteristics"</p>
V02.10	6 Feb 2004	6 Feb 2004		<p>Added A128 information in "Derivative Differences", 2.1 "Device Pinout", 2.2 "Signal Properties Summary", Fig 23-2 & Fig 23-4</p> <p>Added lead-free package option (PVE) in Table 0-2 "Derivative Differences for MC9S12DB128" and Fig 0-1 "Order Partnumber Example"</p> <p>Added an "AEC qualified" row in the "Derivative Differences" tables 0-1 & 0-2.</p>
V02.11	3 May 2004	3 May 2004		<p>Added part numbers SC515846, SC515847, SC515848, and SC515849 in "Derivative Differences" tables 0-1 & 0-2, section 2, and section 23.</p> <p>Corrected and added maskset 4L40K in tables 0-1 & 0-2 and section 1.6.</p> <p>Corrected BDLC module availability in DB128 80QFP part in "Derivative Differences" table 0-2.</p>

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\$0040 - \$007F

ECT (Enhanced Capture Timer 16 Bit 8 Channels)

Address	Name	Read:	Bit 7	Bit 6	Bit 5	Bit 4	Bit 3	Bit 2	Bit 1	Bit 0
\$004A	TCTL3	Write:	EDG7B	EDG7A	EDG6B	EDG6A	EDG5B	EDG5A	EDG4B	EDG4A
\$004B	TCTL4	Read:	EDG3B	EDG3A	EDG2B	EDG2A	EDG1B	EDG1A	EDG0B	EDG0A
\$004C	TIE	Read:	C7I	C6I	C5I	C4I	C3I	C2I	C1I	C0I
\$004D	TSCR2	Read:	TOI	0	0	0	TCRE	PR2	PR1	PR0
\$004E	TFLG1	Read:	C7F	C6F	C5F	C4F	C3F	C2F	C1F	C0F
\$004F	TFLG2	Read:	TOF	0	0	0	0	0	0	0
\$0050	TC0 (hi)	Read:	Bit 15	14	13	12	11	10	9	Bit 8
\$0051	TC0 (lo)	Read:	Bit 7	6	5	4	3	2	1	Bit 0
\$0052	TC1 (hi)	Read:	Bit 15	14	13	12	11	10	9	Bit 8
\$0053	TC1 (lo)	Read:	Bit 7	6	5	4	3	2	1	Bit 0
\$0054	TC2 (hi)	Read:	Bit 15	14	13	12	11	10	9	Bit 8
\$0055	TC2 (lo)	Read:	Bit 7	6	5	4	3	2	1	Bit 0
\$0056	TC3 (hi)	Read:	Bit 15	14	13	12	11	10	9	Bit 8
\$0057	TC3 (lo)	Read:	Bit 7	6	5	4	3	2	1	Bit 0
\$0058	TC4 (hi)	Read:	Bit 15	14	13	12	11	10	9	Bit 8
\$0059	TC4 (lo)	Read:	Bit 7	6	5	4	3	2	1	Bit 0
\$005A	TC5 (hi)	Read:	Bit 15	14	13	12	11	10	9	Bit 8
\$005B	TC5 (lo)	Read:	Bit 7	6	5	4	3	2	1	Bit 0
\$005C	TC6 (hi)	Read:	Bit 15	14	13	12	11	10	9	Bit 8
\$005D	TC6 (lo)	Read:	Bit 7	6	5	4	3	2	1	Bit 0
\$005E	TC7 (hi)	Read:	Bit 15	14	13	12	11	10	9	Bit 8
\$005F	TC7 (lo)	Read:	Bit 7	6	5	4	3	2	1	Bit 0
\$0060	PACTL	Read:	0	PAEN	PAMOD	PEDGE	CLK1	CLK0	PAOVI	PAI
\$0061	PAFLG	Read:	0	0	0	0	0	0	PAOVF	PAIF
\$0062	PACN3 (hi)	Read:	Bit 7	6	5	4	3	2	1	Bit 0

\$00E8 - \$00EF**BDLC (Byte Level Data Link Controller J1850)**

Address	Name	Bit 7	Bit 6	Bit 5	Bit 4	Bit 3	Bit 2	Bit 1	Bit 0
\$00E8	DLCBCR1	Read: IMSG	Write: CLKS	0	0	0	0	IE	WCM
\$00E9		Read: 0	Write: 0	I3	I2	I1	I0		
\$00EA	DLCBCR2	Read: SMRST	Write: DLOOP	RX4XE	NBFS	TEOD	TSIFR	TMIFR1	TMIFR0
\$00EB		Read: D7	Write: D6	D5	D4	D3	D2	D1	D0
\$00EC	DLCBARD	Read: 0	Write: RXPOL	0	0	BO3	BO2	BO1	BO0
\$00ED		Read: 0	Write: 0	R5	R4				
\$00EE	DLCSCR	Read: 0	Write: 0	0	BDLCE	0	0	0	0
\$00EF		Read: 0	Write: 0	0		0	0	0	IDLE

\$00F0 - \$00F7**SPI1 (Serial Peripheral Interface)**

Address	Name	Bit 7	Bit 6	Bit 5	Bit 4	Bit 3	Bit 2	Bit 1	Bit 0
\$00F0	SPI1CR1	Read: SPIE	Write: SPE	SPTIE	MSTR	CPOL	CPHA	SSOE	LSBFE
\$00F1		Read: 0	Write: 0	0	MODFEN	BIDIROE	0	SPISWAI	SPC0
\$00F2	SPI1BR	Read: 0	Write: SPPR2	SPPR1		0	SPR2	SPR1	SPR0
\$00F3		Read: SPIF	Write: 0	SPTEF	MODF	0			
\$00F4	Reserved	Read: 0	Write: 0	0	0	0	0	0	0
\$00F5		Read: Bit7	Write: 6	5	4	3	2	1	Bit0
\$00F6	Reserved	Read: 0	Write: 0	0	0	0	0	0	0
\$00F7		Read: 0	Write: 0	0	0	0	0	0	0

\$00F8 - \$00FF**Reserved**

Address	Name	Bit 7	Bit 6	Bit 5	Bit 4	Bit 3	Bit 2	Bit 1	Bit 0
\$00F8 - \$00FF	Reserved	Read: 0	Write: 0	0	0	0	0	0	0

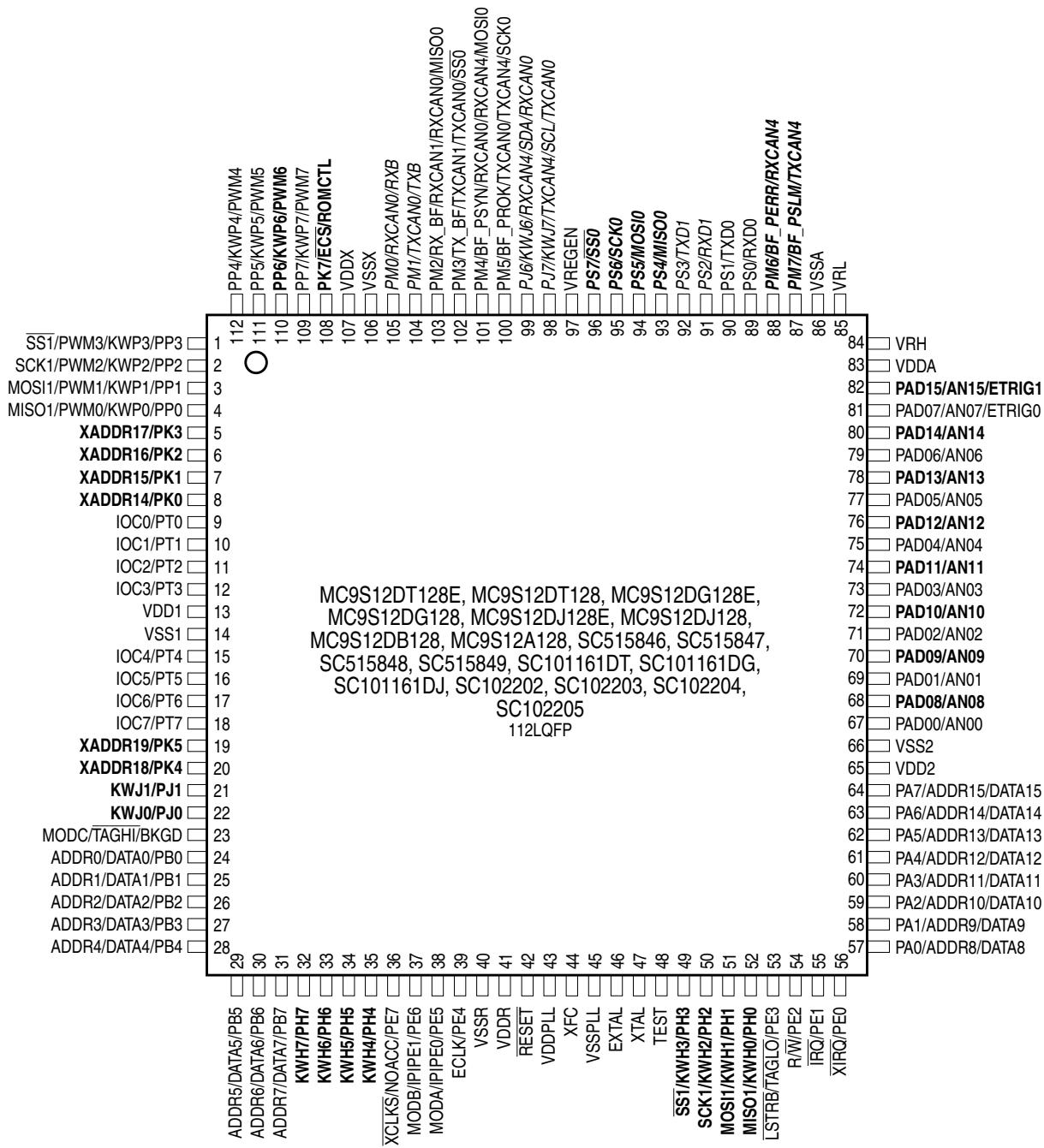
\$0140 - \$017F

CAN0 (Motorola Scalable CAN - MSCAN)

Address	Name	Bit 7	Bit 6	Bit 5	Bit 4	Bit 3	Bit 2	Bit 1	Bit 0
\$0146	CAN0TFLG	Read: 0	0	0	0	0	TXE2	TXE1	TXE0
		Write:							
\$0147	CAN0TIER	Read: 0	0	0	0	0	TXEIE2	TXEIE1	TXEIE0
		Write:							
\$0148	CAN0TARQ	Read: 0	0	0	0	0	ABTRQ2	ABTRQ1	ABTRQ0
		Write:							
\$0149	CAN0TAAK	Read: 0	0	0	0	0	ABTAK2	ABTAK1	ABTAK0
		Write:							
\$014A	CAN0TBSEL	Read: 0	0	0	0	0	TX2	TX1	TX0
		Write:							
\$014B	CAN0IDAC	Read: 0	0	IDAM1	IDAM0	0	IDHIT2	IDHIT1	IDHITO
		Write:							
\$014C	Reserved	Read: 0	0	0	0	0	0	0	0
		Write:							
\$014D	Reserved	Read: 0	0	0	0	0	0	0	0
		Write:							
\$014E	CAN0RXERR	Read: RXERR7	RXERR6	RXERR5	RXERR4	RXERR3	RXERR2	RXERR1	RXERR0
		Write:							
\$014F	CAN0TXERR	Read: TXERR7	TXERR6	TXERR5	TXERR4	TXERR3	TXERR2	TXERR1	TXERR0
		Write:							
\$0150 - \$0153	CAN0IDAR0 - CAN0IDAR3	Read: AC7	AC6	AC5	AC4	AC3	AC2	AC1	AC0
\$0154 - \$0157	CAN0IDMR0 - CAN0IDMR3	Read: AM7	AM6	AM5	AM4	AM3	AM2	AM1	AM0
\$0158 - \$015B	CAN0IDAR4 - CAN0IDAR7	Read: AC7	AC6	AC5	AC4	AC3	AC2	AC1	AC0
\$015C - \$015F	CAN0IDMR4 - CAN0IDMR7	Read: AM7	AM6	AM5	AM4	AM3	AM2	AM1	AM0
\$0160 - \$016F	CAN0RXFG	Read:	FOREGROUND RECEIVE BUFFER see (Table 1-2)						
\$0170 - \$017F		Read:	FOREGROUND TRANSMIT BUFFER see (Table 1-2)						
	Write:								

Table 1-2 Detailed MSCAN Foreground Receive and Transmit Buffer Layout

Address	Name	Bit 7	Bit 6	Bit 5	Bit 4	Bit 3	Bit 2	Bit 1	Bit 0
\$xxx0	Extended ID	Read: ID28	ID27	ID26	ID25	ID24	ID23	ID22	ID21
	Standard ID	Read: ID10	ID9	ID8	ID7	ID6	ID5	ID4	ID3
\$xxx1	CANxRIDR0	Write:							
	Extended ID	Read: ID20	ID19	ID18	SRR=1	IDE=1	ID17	ID16	ID15
\$xxx2	Standard ID	Read: ID2	ID1	ID0	RTR	IDE=0			
	CANxRIDR1	Write:							
\$xxx3	Extended ID	Read: ID14	ID13	ID12	ID11	ID10	ID9	ID8	ID7
	Standard ID	Read: ID1							
\$xxx4-\$xxxB	CANxRIDR2	Write:							
	Extended ID	Read: ID6	ID5	ID4	ID3	ID2	ID1	ID0	RTR
	Standard ID	Read: ID5							
	CANxRIDR3	Write:							
\$xxx4-\$xxxB	CANxRDSR0 - CANxRDSR7	Read: DB7	DB6	DB5	DB4	DB3	DB2	DB1	DB0
	Write:								



Signals shown in **Bold** are not available on all the 80 pin package options

Signals shown in **Bold-Italics** are not available on the MC9S12DJ128E, MC9S12DJ128, MC9S12DG128E, MC9S12DG128, MC9S12A128, SC515847, SC515848, SC101161DG, SC101161DJ, SC102203, and SC102204 80 pin package options

Signals shown in *Italics* are not available on the MC9S12DB128, SC515846, and SC102202 80 pin package options

Figure 2-1 Pin assignments 112 LQFP for MC9S12DT128E, MC9S12DT128, MC9S12DG128E, MC9S12DG128, MC9S12DJ128E, MC9S12DJ128, MC9S12DB128, MC9S12A128, SC515846, SC515847, SC515848, SC515849, SC101161DT, SC101161DG, SC101161DJ, SC102202, SC102203, SC102204, and SC102205

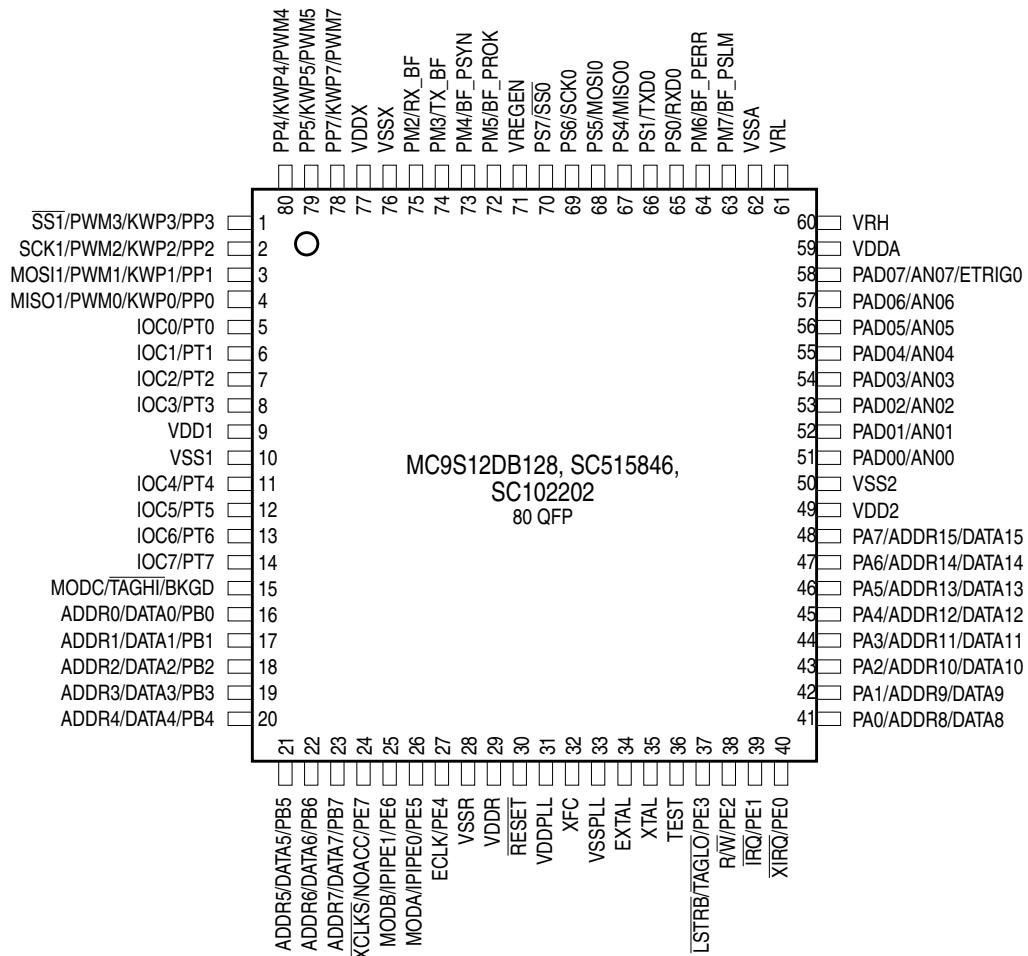


Figure 2-3 Pin Assignments in 80 QFP for MC9S12DB128, SC515846, and SC102202 Bondout

2.2 Signal Properties Summary

(**Table 2-1**) summarizes the pin functionality. Signals shown in **Bold** are not available on all the 80-pin package options. Signals shown in *Bold-Italics* are not available on the MC9S12DG128E, MC9S12DG128, MC9S12DJ128E, MC9S12DJ128, MC9S12A128, SC515847, SC515848, SC101161DG, SC101161DJ, SC102203, and SC102204 80-pin package options. Signals shown in *Italics* are not available on MC9S12DB128, SC515846, and SC102202 80-pin package options.

Section 5 Resets and Interrupts

5.1 Overview

Consult the Exception Processing section of the CPU Reference Manual for information on resets and interrupts.

5.2 Vectors

5.2.1 Vector Table

(Table 5-1) lists interrupt sources and vectors in default order of priority.

Table 5-1 Interrupt Vector Locations

Vector Address	Interrupt Source	CCR Mask	Local Enable	HPrio Value to Elevate
\$FFFE, \$FFFF	Reset	None	None	-
\$FFFC, \$FFFD	Clock Monitor fail reset	None	COPCTL (CME, FCME)	-
\$FFFA, \$FFFB	COP failure reset	None	COP rate select	-
\$FFF8, \$FFF9	Unimplemented instruction trap	None	None	-
\$FFF6, \$FFF7	SWI	None	None	-
\$FFF4, \$FFF5	XIRQ / BF High Priority Sync Pulse	X-Bit	None / BFRIER (XSYNIE)	-
\$FFF2, \$FFF3	IRQ	I-Bit	INTCR (IRQEN)	\$F2
\$FFF0, \$FFF1	Real Time Interrupt	I-Bit	CRGINT (RTIE)	\$F0
\$FFEE, \$FFEF	Enhanced Capture Timer channel 0	I-Bit	TIE (COI)	\$EE
\$FFEC, \$FFED	Enhanced Capture Timer channel 1	I-Bit	TIE (C1I)	\$EC
\$FFEA, \$FFEB	Enhanced Capture Timer channel 2	I-Bit	TIE (C2I)	\$EA
\$FFE8, \$FFE9	Enhanced Capture Timer channel 3	I-Bit	TIE (C3I)	\$E8
\$FFE6, \$FFE7	Enhanced Capture Timer channel 4	I-Bit	TIE (C4I)	\$E6
\$FFE4, \$FFE5	Enhanced Capture Timer channel 5	I-Bit	TIE (C5I)	\$E4
\$FFE2, \$FFE3	Enhanced Capture Timer channel 6	I-Bit	TIE (C6I)	\$E2
\$FFE0, \$FFE1	Enhanced Capture Timer channel 7	I-Bit	TIE (C7I)	\$E0
\$FFDE, \$FFDF	Enhanced Capture Timer overflow	I-Bit	TSCR2 (TOF)	\$DE
\$FFDC, \$FFDD	Pulse accumulator A overflow	I-Bit	PACTL (PAOVI)	\$DC
\$FFDA, \$FFDB	Pulse accumulator input edge	I-Bit	PACTL (PAI)	\$DA
\$FFD8, \$FFD9	SPI0	I-Bit	SPICR1 (SPIE, SPTIE)	\$D8
\$FFD6, \$FFD7	SCI0	I-Bit	SCICR2 (TIE, TCIE, RIE, ILIE)	\$D6
\$FFD4, \$FFD5	SCI1	I-Bit	SCICR2 (TIE, TCIE, RIE, ILIE)	\$D4
\$FFD2, \$FFD3	ATD0	I-Bit	ATDCTL2 (ASCIE)	\$D2
\$FFD0, \$FFD1	ATD1	I-Bit	ATDCTL2 (ASCIE)	\$D0
\$FFCE, \$FFCF	Port J	I-Bit	PIEJ (PIEJ7, PIEJ6, PIEJ1, PIEJ0)	\$CE
\$FFCC, \$FFCD	Port H	I-Bit	PIEH (PIEH7-0)	\$CC

15.1 Device-specific information

The read-only Module Version Register (BFMVR) contains the current version number of \$80.

Section 16 Pulse Width Modulator (PWM) Block Description

Consult the PWM_8B8C Block User Guide for information about the Pulse Width Modulator module. When the PWM_8B8C Block User Guide refers to *freeze mode* this is equivalent to *active BDM mode*.

Section 17 Flash EEPROM 128K Block Description

Consult the FTS128K Block User Guide for information about the flash module.

Section 18 EEPROM 2K Block Description

Consult the EETS2K Block User Guide for information about the EEPROM module.

Section 19 RAM Block Description

This module supports single-cycle misaligned word accesses without wait states.

Section 20 MSCAN Block Description

There are three MSCAN modules (CAN4, CAN1 and CAN0) implemented on the MC9S12DT128. Consult the MSCAN Block User Guide for information about the Motorola Scalable CAN Module.

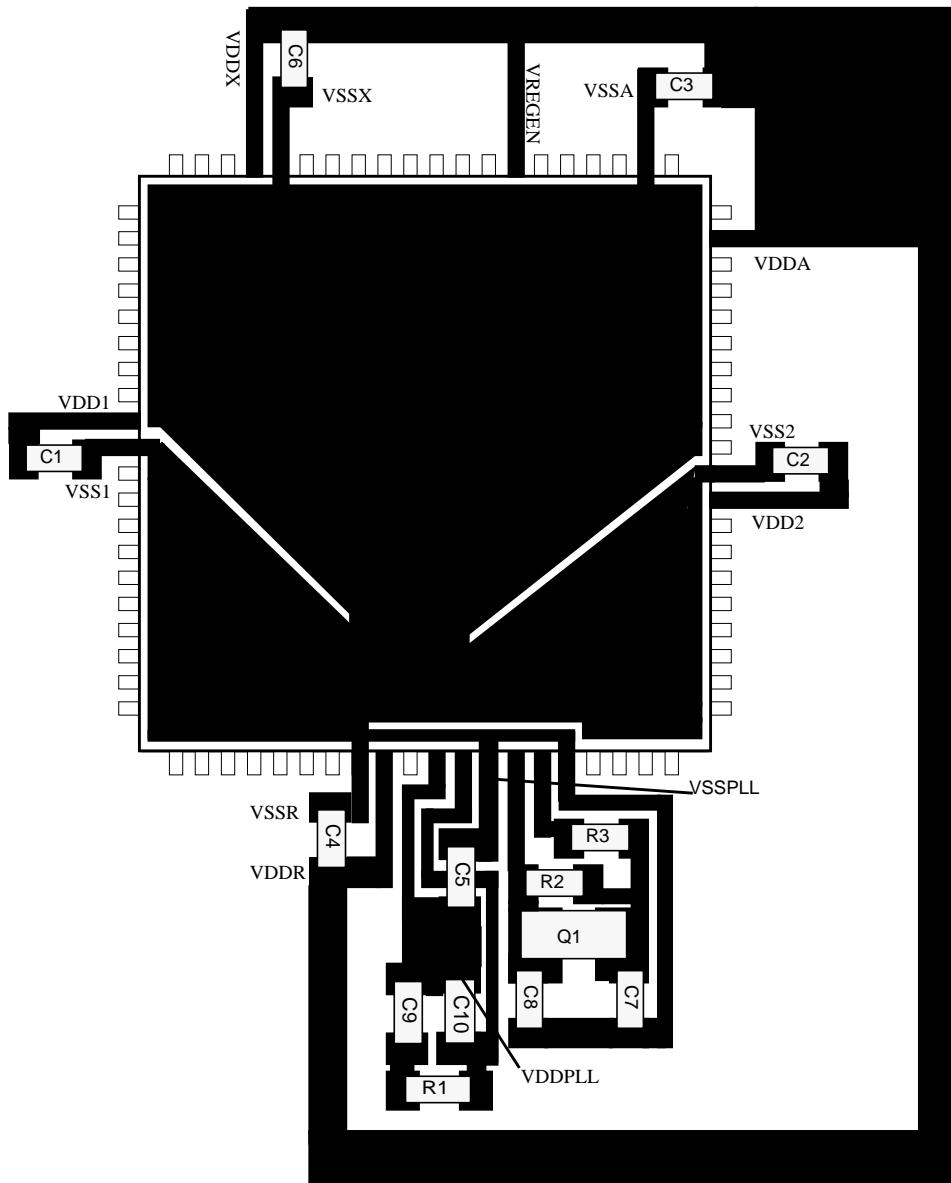
Section 21 Port Integration Module (PIM) Block Description

Consult the PIM_9DTB128 Block User Guide for information about the Port Integration Module.

Section 22 Voltage Regulator (VREG) Block Description

Consult the VREG Block User Guide for information about the dual output linear voltage regulator.

Figure 23-4 Recommended PCB Layout for 80QFP (MC9S12DG128E, MC9S12DG128, MC9S12DJ128E, MC9S12DJ128, MC9S12A128, SC515847, SC515848, SC101161DG, SC101161DJ, SC102203, and SC102204) Pierce Oscillator



NOTES:

1. PLL off, Oscillator in Colpitts Mode
2. At those low power dissipation levels $T_J = T_A$ can be assumed

A.2 ATD Characteristics

This section describes the characteristics of the analog to digital converter.

A.2.1 ATD Operating Characteristics

The (**Table A-8**) shows conditions under which the ATD operates.

The following constraints exist to obtain full-scale, full range results:

$V_{SSA} \leq V_{RL} \leq V_{IN} \leq V_{RH} \leq V_{DDA}$. This constraint exists since the sample buffer amplifier can not drive beyond the power supply levels that it ties to. If the input level goes outside of this range it will effectively be clipped.

Table A-8 ATD Operating Characteristics

Conditions are shown in (Table A-4) unless otherwise noted							
Num	C	Rating	Symbol	Min	Typ	Max	Unit
1	D	Reference Potential	V_{RL} V_{RH}	V_{SSA} $V_{DDA}/2$		$V_{DDA}/2$ V_{DDA}	V V
2	C	Differential Reference Voltage ¹	$V_{RH}-V_{RL}$	4.50	5.00	5.25	V
3	D	ATD Clock Frequency	f_{ATDCLK}	0.5		2.0	MHz
4	D	ATD 10-Bit Conversion Period	N_{CONV10} T_{CONV10}	14 7		28 14	Cycles μ s
5	D	ATD 8-Bit Conversion Period	N_{CONV8} T_{CONV8}	12 6		26 13	Cycles μ s
6	D	Stop Recovery Time ($V_{DDA}=5.0$ Volts)	t_{SR}			20	μ s
7	P	Reference Supply current (Both ATD modules on)	I_{REF}			0.75	mA
8	P	Reference Supply current (Only one ATD module on)	I_{REF}			0.375	mA

NOTES:

1. Full accuracy is not guaranteed when differential voltage is less than 4.50V
2. The minimum time assumes a final sample period of 2 ATD clock cycles while the maximum time assumes a final sample period of 16 ATD clocks.

A.2.2 Factors influencing accuracy

Three factors – source resistance, source capacitance and current injection – have an influence on the accuracy of the ATD.

A.2.2.1 Source Resistance:

Due to the input pin leakage current as specified in (**Table A-6**) in conjunction with the source resistance there will be a voltage drop from the signal source to the ATD input. The maximum source resistance R_S

specifies results in an error of less than 1/2 LSB (2.5mV) at the maximum leakage current. If device or operating conditions are less than worst case or leakage-induced error is acceptable, larger values of source resistance is allowed.

A.2.2.2 Source capacitance

When sampling an additional internal capacitor is switched to the input. This can cause a voltage drop due to charge sharing with the external and the pin capacitance. For a maximum sampling error of the input voltage $\leq 1\text{LSB}$, then the external filter capacitor, $C_f \geq 1024 * (C_{INS} - C_{INN})$.

A.2.2.3 Current injection

There are two cases to consider.

1. A current is injected into the channel being converted. The channel being stressed has conversion values of \$3FF (\$FF in 8-bit mode) for analog inputs greater than V_{RH} and \$000 for values less than V_{RL} unless the current is higher than specified as disruptive conditions.
2. Current is injected into pins in the neighborhood of the channel being converted. A portion of this current is picked up by the channel (coupling ratio K). This additional current impacts the accuracy of the conversion depending on the source resistance.

The additional input voltage error on the converted channel can be calculated as $V_{ERR} = K * R_s * I_{INJ}$, with I_{INJ} being the sum of the currents injected into the two pins adjacent to the converted channel.

Table A-9 ATD Electrical Characteristics

Conditions are shown in (Table A-4) unless otherwise noted							
Num	C	Rating	Symbol	Min	Typ	Max	Unit
1	C	Max input Source Resistance	R_s	-	-	1	$\text{k}\Omega$
2	T	Total Input Capacitance Non Sampling Sampling	C_{INN} C_{INS}			10 22	pF
3	C	Disruptive Analog Input Current	I_{NA}	-2.5		2.5	mA
4	C	Coupling Ratio positive current injection	K_p			10^{-4}	A/A
5	C	Coupling Ratio negative current injection	K_n			10^{-2}	A/A

$$t_{era} \approx 4000 \cdot \frac{1}{f_{NVMOP}}$$

The setup time can be ignored for this operation.

A.3.1.4 Mass Erase

Erasing a NVM block takes:

$$t_{mass} \approx 20000 \cdot \frac{1}{f_{NVMOP}}$$

The setup time can be ignored for this operation.

A.3.1.5 Blank Check

The time it takes to perform a blank check on the Flash or EEPROM is dependant on the location of the first non-blank word starting at relative address zero. It takes one bus cycle per word to verify plus a setup of the command.

$$t_{check} \approx \text{location} \cdot t_{cyc} + 10 \cdot t_{cyc}$$

Table A-11 NVM Timing Characteristics

Conditions are shown in (Table A-4) unless otherwise noted							
Num	C	Rating	Symbol	Min	Typ	Max	Unit
1	D	External Oscillator Clock	f_{NVMOsc}	0.5		50 ¹	MHz
2	D	Bus frequency for Programming or Erase Operations	f_{NVMbus}	1			MHz
3	D	Operating Frequency	f_{NVMOP}	150		200	kHz
4	P	Single Word Programming Time	t_{swpgm}	46 ²		74.5 ³	μs
5	D	Flash Row Programming consecutive word ⁴	t_{bwpgm}	20.4 ⁽²⁾		31 ⁽³⁾	μs
6	D	Flash Row Programming Time for 32 Words ⁽⁴⁾	t_{brpgm}	678.4 ⁽²⁾		1035.5 ⁽³⁾	μs
7	P	Sector Erase Time	t_{era}	20 ⁵		26.7 ⁽³⁾	ms
8	P	Mass Erase Time	t_{mass}	100 ⁽⁵⁾		133 ⁽³⁾	ms
9	D	Blank Check Time Flash per block	t_{check}	11 ⁶		32778 ⁷	t_{cyc}
10	D	Blank Check Time EEPROM per block	t_{check}	11 ⁽⁶⁾		1034 ⁽⁷⁾	t_{cyc}

NOTES:

1. Restrictions for oscillator in crystal mode apply!
2. Minimum Programming times are achieved under maximum NVM operating frequency f_{NVMOP} and maximum bus frequency f_{bus} .
3. Maximum Erase and Programming times are achieved under particular combinations of f_{NVMOP} and bus frequency f_{bus} . Refer to formulae in Sections **Section A.3.1.1 Single Word Programming- Section A.3.1.4 Mass Erase** for guidance.
4. Row Programming operations are not applicable to EEPROM
5. Minimum Erase times are achieved under maximum NVM operating frequency f_{NVMOP} .
6. Minimum time, if first word in the array is not blank
7. Maximum time to complete check on an erased block

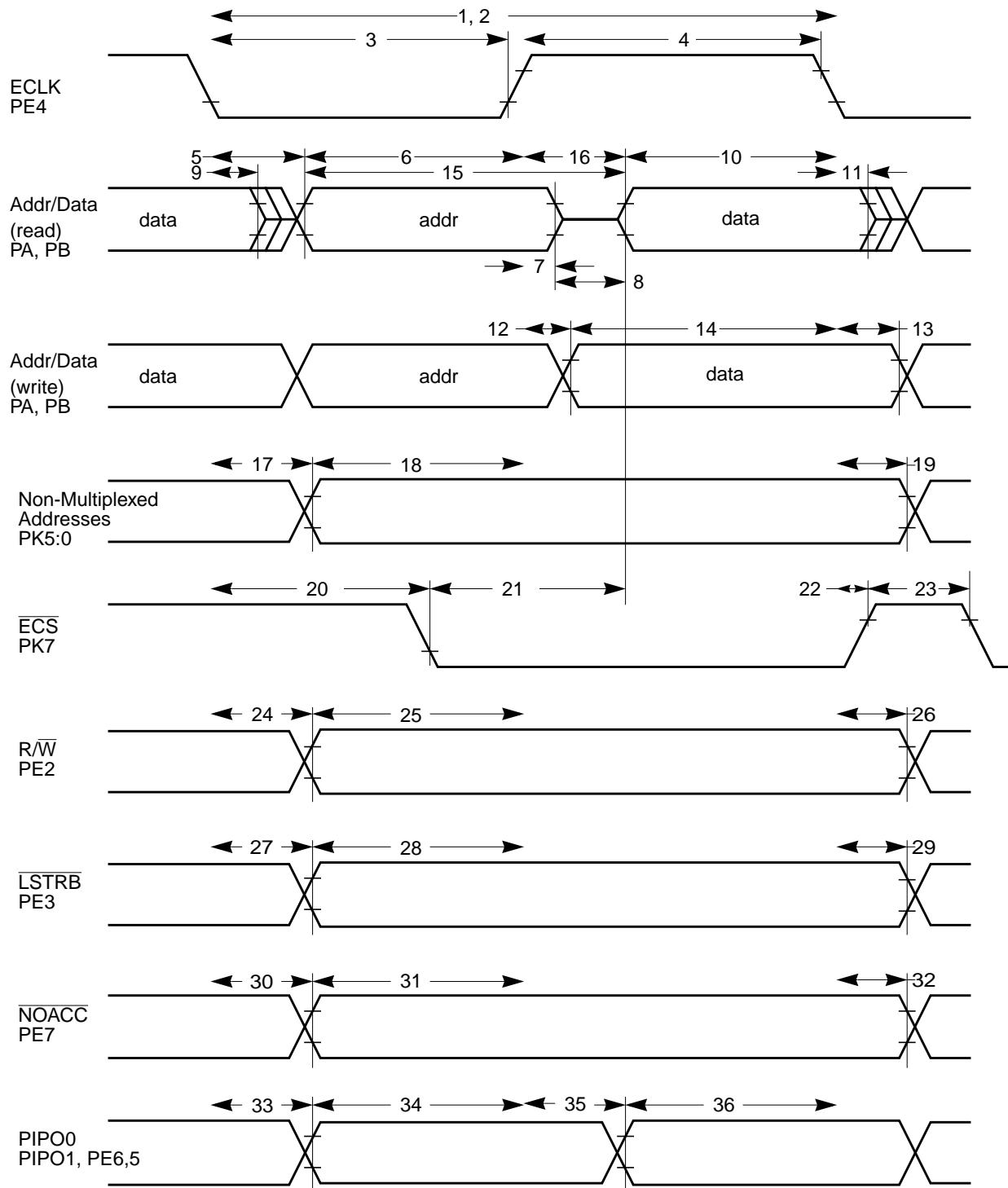


Figure A-10 General External Bus Timing

Appendix B Package Information

B.1 General

This section provides the physical dimensions of the MC9S12DT128 packages.

